

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Morito AKIYAMA et al.

Atty. Ref.: 1035-548

Serial No. 10/516,333

TC/A.U.: unassigned

Filed: November 30, 2004

Examiner: unassigned

For: PIEZOELECTRIC ELEMENT BASED ON SUPERHIGH-ORIENTED ALUMINUM NITRIDE THIN FILM AND MANUFACTURING METHOD

THEREOF

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January 4, 2005

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449.

| All listed documents are attached. |
|---|
| Copies of U.S. Patent Publications are not required and are not attached. |
| Listed foreign patent publications and other documents are enclosed. |
| ☐ The listed documents were cited in the ISR and copies should have been |
| supplied by WIPO directly to the US PTO. If copies are not timely received from WIPO, |
| please telephone the undersigned so that copies can be timely supplied for the Examiner's |
| consideration in this US National Phase Application. |

This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Morito AKIYAMA et al. Serial No. 10/516,333

Respectfully submitted,

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*Examiner

INFORMATION DISCLOSURE CITATION

eral sheets if necessary)

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ATTY, DOCKET NO.

SERIAL NO.

1035-548

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APPLICANT

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November 30, 2004

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| TRACE | · · - · · · | 11010 | UI. | assigned | | | |
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| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING IF APPRO | |
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Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Date Considered